TOSHIBA 2SC5323

TENTATIVE

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL PLANAR TYPE

2 S C 5 3 2 3

VHF~UHF BAND LOW NOISE AMPLIFIER APPLICATIONS

: NF = 1.4 dB (f = 2 GHz)Low Noise Figure High Gain : Ga = 12 dB (f = 2 GHz)

MAXIMUM RATINGS (Ta = 25°C)

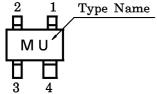
CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	8	V
Collector-Emitter Voltage	v_{CEO}	5	V
Emitter-Base Voltage	$v_{ m EBO}$	1.5	V
Collector Current	$I_{\mathbf{C}}$	10	mA
Base Current	$I_{\mathbf{B}}$	5	mA
Collector Power Dissipation	$P_{\mathbf{C}}$	150	mW
Junction Temperature	T_{j}	125	°C
Storage Temperature Range	$\mathrm{T_{stg}}$	-55~125	°C

MARKING

+ 0.2 2.9 - 0.3 2.9 ± 0.2 90 0.85 0.55 + 0.25 1.50 - 0.15 0.05 ± 0.05 1, 3. EMITTER 2. BASE **COLLECTOR** 4. **JEDEC EIAJ TOSHIBA** 2-3J1C

Unit in mm

Weight: 0.012 g



MICROWAVE CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Transition Frequency	$ m f_{T}$	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}$	13	16	_	GHz
Unsertion (tain	$ S_{21e} ^2$ (1)	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}, f = 1 \text{ GHz}$	14.5	17.5	_	dB
	$ S_{21e} ^2$ (2)	$V_{CE} = 3 \text{ V}, I_{C} = 7 \text{ mA}, f = 2 \text{ GHz}$	9	12	_	
Noise Figure	NF (1)	$V_{ m CE}=3~{ m V},~{ m I}_{ m C}=3~{ m mA},~{ m f}=1~{ m GHz}$		0.9	1.8	dB
	NF (2)	$V_{CE} = 3 \text{ V}, I_{C} = 3 \text{ mA}, f = 2 \text{ GHz}$	_	1.4	2.3	լ ահ

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Collector Cut-off Current	I_{CBO}	$V_{CB} = 8 V, I_{E} = 0$	_	_	1	μ A
Emitter Cut-off Current	I_{EBO}	$V_{EB} = 1 V, I_{C} = 0$	_	_	1	μ A
DC Current Gain	$_{ m h_{FE}}$	$V_{CE} = 3 V, I_{C} = 7 mA$	50	_	250	V
Output Capacitance	C_{ob}	$V_{CB} = 2.5 \text{ V}, I_{E} = 0,$	_	0.4	_	pF
Reverse Transfer Capacitance	C_{re}	f = 1 MHz (Note)	_	0.3	0.7	pF

(Note): Cre is measured by 3 terminal method with Capacitance Bridge. **CAUTION**

This device electrostatic sensitivity. Please handle with caution.

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